Designing a Variables Two-Plan Sampling System with Process Loss Consideration

Nani Kurniati
Department of Industrial Management
National Taiwan University of Science and Technology
Taipei 10607, Taiwan

Chien-Wei Wu
Department of Industrial Engineering and Engineering Management
National Tsing Hua University
Hsinchu 30013, Taiwan

Ruey-Huei Yeh
Department of Industrial Management
National Taiwan University of Science and Technology
Taipei 10607, Taiwan

Abstract

Acceptance sampling had become an essential practical tool for quality assurance application, closely related with incoming inspection. Acceptance sampling plans provide the decision rule for product acceptance to meet the preset product quality required by the vendor and the buyer. As today’s modern paradigm of quality improvement, reduction of variance from the target value is the guiding principle as well as reduction on fraction of defective. The $C_{pm}$ index particularly adopts the loss function approach, which distinguishes product quality by increasing penalty to products deviating from the target. This paper proposes variables two-plan sampling system based on process capability index $C_{pm}$ that takes into account departures from target value as well as changes in the process variation. The operating procedure and the conditions to determine the plan parameter are provided. The plan parameter of the proposed sampling plans determine effectively by solving the two nonlinear equations simultaneously. The behavior of the proposed two-plan sampling system is also discussed. For practical purpose, table of the required sample size and the corresponding critical acceptance value under various parameter settings is provided.

Keywords
Product acceptance determination; process capability analysis; variables two-plan sampling system; process loss

1. Introduction

Inspection of incoming products is an integral part of the order and quality contract between vendor and buyer. For this purpose, acceptance sampling had become one of the essential statistical tools that provide vendor and buyer decision rules for product acceptance determination to meet their quality requirement. Acceptance sampling majorly classified as variables and attributes. It has been investigated that variables sampling has more advantage over attributes sampling. Under the same protection both to the vendor and the buyer, variables sampling would require less sampling compare to attributes sampling (Montgomery 2009). Even the inspection in variable sampling is costly, the significant reduction on sample number will more than offset the increasing cost due to time consuming especially when employed the destructive test.

Sampling system is a collection of two or more sampling plans together with criteria by which appropriate plans may be chosen and the switching rules as well (Schiling and Neubauer 2009). A sampling system involve only normal and tightened sampling plan consider as tightened-normal-tightened (TNT) system, simply called two-plan...
system. Tightened inspection will be used when the supplier’s recent quality has deteriorated and normal inspection will be used when the quality is found to be very good.

Calvin (1977) firstly utilized two single-sampling plans for attribute—TNT-TN(, ; 0 ) take T
nn sample size for tightened inspection, N
nn sample size for normal inspection, and apply zero acceptance number. Several studies have made on variables two-plan sampling system, say Muthuraj and Senthilkumar (2006), Senthilkumar and Muthuraj (2010), and Balamurali and Jun (2009). However, the existing variable TNT systems are designed specifically for process with one-sided specification limit. All are applied approximation approach by assuming the quality characteristic follow normal distribution.

Modern’s paradigm of quality improvement has championed by Taguchi (Taguchi, 1986) in which reduction of variance from the target value is the guiding principle as well as reduction on fraction of defective (Boyle, 1991 and Pearn and Wu, 2006). The index C
pm measures the ability of the process to cluster around the target and reflect the degree of process centering. The C
pm index particularly adopts the loss function approach, which distinguishes product quality by considering cost of deviating quality characteristic from the target value. This C
pm index also called loss-based index or Taguchi index.

In this paper, we developed a two-plan sampling system based on C
pm index for lot sentencing using measurement data required by variables sampling. The proposed sampling plan is based on exact sampling distribution rather than approximation. Hence, the decisions made are more accurate and reliable. The concept of C
pm index is reviewed, and the development of the proposed sampling system is discussed. The behaviors of the proposed method accompanied by the tabulated solved plan parameters are also provided.

2. Process Capability Index C
pm

Process capability indices (PCI’s) include C
p and C
pk have been widely used in manufacturing industry as a unitless measure of the capability process to produce items meeting the quality/reliability requirement preset in factory (Kane, 1986) . Hsiang and Taguchi (1985) and Chan et al. (1988) separately introduced the C
pm index, and further note as first-generation modification. The C
pm index incorporates two components—the target value and the process variability. The C
pm index is defined as
\[
C_{pm} = \frac{USL - LSL}{6\sigma + (\mu - T)^2} = \frac{USL - LSL}{6\sqrt{\sigma^2 + (\mu - T)^2}}. 
\]
where USL and LSL are the upper and lower specification limits of the process,
\(\sigma\) is standard deviation from target,
\(\mu\) is the process mean,
\(T\) is the process target, and
\(\sqrt{\sigma^2 + (\mu - T)^2}\) is the deviation of the process mean from the target. Boyle (1991) provides the estimator of
\(C_{pm} = \hat{C}_{pm}\) defined as
\[
\hat{C}_{pm} = \frac{USL - LSL}{6\sqrt{s_n^2 + (\bar{X} - T)^2}}. 
\]
where
\[
\bar{X} = \frac{1}{n} \sum_{i=1}^{n} x_i 
\] and
\[
s_n^2 = \frac{1}{n} \sum_{i=1}^{n} (X_i - \bar{X})^2
\] are the maximum likelihood estimators of \(\mu\) and \(\sigma^2\), respectively.

Under normally distributed process, the CDF of \(\hat{C}_{pm}\) is expressed as mixture of the chi-square and normal distributions as follow (Chan et al., 1988)
\[
F_{\hat{C}_{pm}}(y) = 1 - \int_0^{\frac{1}{2}\left(\frac{\xi}{y}\right)^{1/2}} G \left( \frac{b^2 n}{y^2 - t^2} \right) \times \left[ \phi(t + \xi \sqrt{n}) + \phi(t - \xi \sqrt{n}) \right] dt \quad (1)
\]
for \(y \geq 0\), where \(b = 3C_{pm}\sqrt{1 + \xi^2}\), \(\xi = (\mu - T)/\sigma\), \(G()\) is the CDF of the chi-square distribution with degree of freedom \(n - 1\), \(\chi_{n-1}^2\), \(\phi()\) is the probability density function of the standard normal distribution \(N(0,1)\). For fixed values of \(y\) and \(n\), we would obtain the identical equation if \(\xi\) is substituted by \(-\xi\).

3. Designing two-plan system based on C
pm

Consider the quality characteristic of interest has both the lower and the upper specification limit as the acceptable value and follows normal distribution, the operating procedure of the proposed two-plan system as follows:
Step 1: Conduct inspection under tightened single sampling plan with sample size \( n_t \) and critical acceptance value \( k \). Accept the lot if \( \hat{C}_{pm} \geq k \). When \( t \) lots in a row are accepted then switch to normal inspection.

Step 2: Conduct inspection under normal single sampling plan with sample size \( n_n \) and critical acceptance value \( k \). Reject the lot if \( \hat{C}_{pm} < k \). When an additional lot is rejected in the next \( s \) lots after rejection, switch to tightened inspection.

Thus, the plan parameters include \( n_t, n_n, k, t, \) and \( s \). Where \( n_t \) and \( n_n \) are sample size under tightened and normal inspection respectively, \( k \) is acceptance criteria, \( t \) and \( s \) are the switching criteria to normal and tightened inspection respectively.

The variables two-plan system undergoes as long as production is steady. The lots are submitted as the order of production and expected to have the same quality. If the quality of the submitted lot is \( C_{pm} \), the performance measure in terms of the probability of acceptance for a single inspection, known as operating characteristic (OC) function based on the \( C_{pm} \) index is:

\[
P_a(C_{pm}) = P(\hat{C}_{pm} > k) = 1 - P(\hat{C}_{pm} < k) = 1 - F_{\hat{C}_{pm}}(y)
\]

According to Calvin (1977), for the two-plan system, the cumulative probability of acceptance, known as the eventual probability of acceptance, \( \pi_s(C_{pm}) \), is given by

\[
\pi_s(C_{pm}) = \frac{P_s(C_{pm}) \left(1 - P_t(C_{pm})\right) \left(1 - P_t(C_{pm})\right) \left[1 - P_t(C_{pm})\right] + P_t(C_{pm}) \left[1 - P_t(C_{pm})\right] \left(1 - P_t(C_{pm})\right) \left[2 - P_t(C_{pm})\right]}{\left(1 - P_t(C_{pm})\right) \left(1 - P_t(C_{pm})\right) \left[1 - P_t(C_{pm})\right] + P_t(C_{pm}) \left[1 - P_t(C_{pm})\right] \left(2 - P_t(C_{pm})\right)}
\]

where \( P_s(C_{pm}) \) and \( P_t(C_{pm}) \) are the probability of lot acceptance based on \( C_{pm} \) under tightened and normal sampling plans, respectively.

The proposed sampling system is determined by contract between vendor and buyer with certain desirable risk. In order to design the two-plan system with specified OC curve, a commonly used approach is to require that the OC curve pass through two specified points e.g \( (AQL, 1 - \alpha) \) and \( (RQL, \beta) \). Where \( AQL \) and \( RQL \) are the capability requirements corresponding to the AQL (acceptable quality level) and RQL (rejectable quality level) based on the \( C_{pm} \) index, respectively, AQL represents the lowest level of quality for vendor’s process that buyer consider acceptable as process average. RQL represents the lowest level of quality that buyer is willing to accept. The probability of acceptance must be greater than \( 100(1 - \alpha)\% \) if the quality level of submitted lot is at AQL. While the quality level of submitted lot is at RQL, the probability of acceptance would be no more than \( 100\beta\% \). Hence, the plan parameters are the solution to the following two nonlinear equations simultaneously.

\[
\pi_s(C_{AQL}) \geq 1 - \alpha
\]

and

\[
\pi_s(C_{RQL}) \leq \beta
\]

Under certain value of \( s \) and \( t \), the three plan parameters \( (n_t, n_n, k) \) should be determined. There will be several possible solutions that satisfy the two conditions. Hence, the adjustment may consider that the sample size for tightened inspection \( n_t \) must greater than the sample size of normal inspection \( n_n \). \( n_t \) can be considered as multiplication of \( n_n \) with a value of \( m \) (\( m > 1 \)) i.e \( n_t = m \times n_n \), as suggested by Soundararajan and Vijayaraghavan (1992). It is necessary to keep that number of sample for tightened inspection \( n_t \) always larger than number of sample for normal inspection \( n_n \), \( (n_t > n_n) \). Then, the only parameter left need to be determined is \( (n_n, k) \), under
the given value of \( m, s, \) and \( t \). The required sample size \( n_N \) is the least possible integer value of \( n_N \) satisfying Eqs. (4) and (5). Moreover, to illustrate how we solve the above two nonlinear simultaneous equations, let

\[
S_1(n_N; k) = \pi_A(C_{AQL}) - (1 - \alpha)
\]

and

\[
S_2(n_N; k) = \pi_A(C_{RQL}) - \beta
\]

4. Computation and Discussion

The extensive calculations are performed to obtain the plan parameters under various combinations of the entry parameter for convenience application. In order to show how to solve the two nonlinear simultaneous equations, some figures are presented. Under \( (C_{AQL}, C_{RQL}) = (1.50,1.00), (\alpha, \beta) = (0.05,0.01), (s,t) = (1,1), \) and \( m = 1.5 \), Fig.1(a) display the surface and (b) contour plots of Eqs. (6) and (7) simultaneously. From Fig. 1 we determine the plan parameters as the intersection between \( S_1(n_N; k) \) and \( S_2(n_N; k) \) at level 0, which is result \( (n_N; k) = (40;1.2693) \).

Regarding to the switching rule \( (s,t) \), we examine several possible pairs as suggested by Muthuraj and Senthilkumar (2006) \(- (s,t) = (1,1),(1,2),(2,3), \) and \( (4,5) \). The investigation of the effect of different switching rule can be explained by the OC curve as present in Fig.2. Under \( (C_{AQL}, C_{RQL}) = (1.50,1.00), (\alpha, \beta) = (0.05,0.01), \) and \( m = 3 \), it is clearly observed that the combination of \( (s,t) = (4,5) \) have more steeper OC curve. This pattern also work for another plan under any value of \( m \). Means that the proposed sampling system has more discriminatory power compare to traditional single sampling plan (Wu and Pearn, 2006) i.e when \( (s,t) = (1,1) \) and \( m = 1 \). Therefore, we are focusing the analysis of the proposed two-plan sampling system under the switching rule \( (s,t) = (4,5) \).

![Fig. 1. (a) the surface and (b) contour plots of the simultaneously solution of \( S_1(n_N; k) \) and \( S_2(n_N; k) \)](image-url)
For convenience application of the proposed two-plan system to practitioners, we calculate and tabulate the plan parameters \((n_n,k)\) under various quality level \(\left(C_{AQL}, C_{RQL}\right)\), producer’s risk \(\alpha\), and consumer’s risk \(\beta\), multiplication number \(m\), for \(s,t\) = (4,5) as provided at Table 1. For instance, under \(\left(C_{AQL}, C_{RQL}\right) = (1.50, 1.00)\), \((\alpha, \beta) = (0.10, 0.05)\), and \(m = 2\), then \(n_n = 18\) and \(n_c = 36\) should be sampled for normal and tightened inspection respectively with critical value \(k = 1.2522\). First conduct inspection under tightened single sampling plan by take 36 samples and accept the lot if \(\hat{C}_{pm} \geq 1.2522\). If 5 lots in a row are accepted, then switch to normal inspection. Following inspection conduct by take 18 samples from the lot and reject the lot if \(\hat{C}_{pm} < 1.2522\). If an additional lot is rejected in the next \(s = 4\) lots after rejection, switch to tightened inspection. This sampling plan will protect the buyer from making the wrong decision to accept the bad lot with probability 5%, and protect the vendor from the wrong decision to reject the good lot with probability 90%.

### Table 1. The plan parameter \((n_n,k)\) under various value of \(\left(C_{AQL}, C_{RQL}\right)\), \((\alpha, \beta)\), and \(m\)

<table>
<thead>
<tr>
<th>(\left(C_{AQL}, C_{RQL}\right))</th>
<th>(\alpha)</th>
<th>(\beta)</th>
<th>(m = 1.5)</th>
<th>(m = 2)</th>
</tr>
</thead>
<tbody>
<tr>
<td>(1.33, 1.00)</td>
<td>0.05</td>
<td>0.01</td>
<td>78</td>
<td>117.7726</td>
</tr>
<tr>
<td></td>
<td>0.1</td>
<td>0.05</td>
<td>42</td>
<td>117.4918</td>
</tr>
<tr>
<td>(1.50, 1.00)</td>
<td>0.05</td>
<td>0.01</td>
<td>39</td>
<td>126.9418</td>
</tr>
<tr>
<td></td>
<td>0.1</td>
<td>0.05</td>
<td>21</td>
<td>126.7384</td>
</tr>
</tbody>
</table>

### 5. Conclusion
This study attempt to construct two-plan sampling system based on capability index \(C_{pm}\). The operating characteristic (OC) curve of the proposed sampling system is derived based on exact sampling distribution and it is required to pass two designed point. The plan parameters are determined by solving two non-linear equations in order to satisfy the producer’s and consumer’s risk simultaneously. For convenience practical application of the proposed sampling system, the table of the plan parameters is provided. The pattern and behavior of the proposed two-plan sampling system are discussed under several setting of parameter. The comparison between the proposed sampling system and traditional single sampling plan provide the advantage of the proposed plan. The proposed two-plan sampling system can be considered as generalization of the sampling plan. It will reduce to traditional single sampling plan for \((s,t) = (1,1)\) and \(m = 1\).
References


Biography

**Nani Kurniati** is currently a PhD student in the Department of Industrial Management, National Taiwan University of Science and Technology (NTUST), Taiwan. She earned B.S in Industrial Engineering from Institut Teknologi Sepuluh Nopember (ITS), Indonesia, and Masters in Industrial Engineering and Management from Institut Teknologi Bandung (ITB), Indonesia. Previously, she is a fulltime lecturer in the Industrial Engineering Department at Institut Teknologi Sepuluh Nopember (ITS), Indonesia. Her research interests include quality engineering, statistical process control, reliability analysis, maintenance management, and warranty analysis. Nani Kurniati can be contacted at d10001804@mail.ntust.edu.tw

**Chien-Wei Wu** is currently a Professor in the Department of Industrial Engineering and Engineering Management at National Tsing Hua University (NTHU), Taiwan. Dr. Wu received his Ph.D. degree in Industrial Engineering and Management with Outstanding Ph.D Student Award from National Chiao Tung University, the M.S. degree in Statistics from National Tsing Hua University and the B.S. degree in Applied Mathematics with the Phi Tao Phi Honor from National Chung Hsing University. He worked for National Taiwan University of Science and Technology (NTUST) and Feng Chia University (FCU) before he joined NTHU. Dr. Wu has received many achievement awards recently. He is also serving as one of Editors-in-Chief of *Quality Technology and Quantitative Management* (QTQM) (SCI-E indexed) and editorial board members for various international journals. His research interests include quality engineering and management, statistical process control, process capability analysis, applied statistics and data analysis.

**Ruey-Huei Yeh** is currently a Vice President in National Taiwan University of Science and Technology (NTUST), Taiwan and Distinguished Professor in the Department of Industrial Management at NTUST. He received B.S. in Industrial Engineering and Engineering Management Department at National Tsing Hua University (NTHU), Taiwan, and M.S. & Ph.D. in the University of Michigan, Ann Arbor, U.S.A. His research interest includes reliability analysis, decision analysis, quality control, and warranty policies. He is currently an associate editor of *IEEE Transactions on Reliability.*